L Number	Hits	Search Text	DB	Time stamp
2	312	714/37.ccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/07/28 08:59
3	298	714/39.ccls. and @ad<=20011023	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/07/28 08:59
1	255	714/57.ccls. and @ad<=20011023	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/07/28 08:59
4	321	714/45.ccls. and @ad<=20011023	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/28 08:59
5	376	714/46.ccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/28 08:59
6	601	714/48.ccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/28 08:59
7	134	((714/37.ccls. and @ad<=20011023) (714/39.ccls. and @ad<=20011023) (714/45.ccls. and @ad<=20011023) (714/46.ccls. and @ad<=20011023) (714/48.ccls. and @ad<=20011023)) and tester	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28
8	776	714/736.ccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/28 09:02
9	129	714/745.ccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/28 09:02
10	260	((714/736.ccls. and @ad<=20011023) (714/745.ccls. and @ad<=20011023)) and tester	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 09:02
_	6	(UCHIYAMA-HIROTO).in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 10:00
-	50	((714/37.ccls. and @ad<=20011023) (714/39.ccls. and @ad<=20011023) (714/45.ccls. and @ad<=20011023) (714/46.ccls. and @ad<=20011023) (714/48.ccls. and @ad<=20011023) (714/704.ccls. and @ad<=20011023) (714/736.ccls. and @ad<=20011023) (714/745.ccls. and @ad<=20011023) (714/745.ccls. and @ad<=20011023)) and (("IC" or "integrated circuit") adj tester)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 14:50

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Γ	333	(("IC" or "integrated circuit") adj	USPAT;	2004/07/26
-	333	tester) and (sample or sampling)	US-PGPUB;	08:34
		coscer, and (sample of sampling)	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	286	((("IC" or "integrated circuit") adj	USPAT;	2004/07/26
		tester) and (sample or sampling)) and	US-PGPUB;	08:40
		@ad<=20011023	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	3326	("IC" or "integrated circuit") adj tester	USPAT;	2004/07/26
		, 25 52	US-PGPUB;	14:04
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
	3	(("IC" or "integrated circuit") adj	USPAT;	2004/07/26
		tester) and (mu and sigma)	US-PGPUB;	14:05
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	İ
_	22		USPAT;	2004/07/26
		tester) and ((standard adj deviation) and	US-PGPUB;	14:10
		(average or mean))	EPO; JPO;	
		-	DERWENT;	
			IBM_TDB	
_	904	714/704.ccls. and @ad<=20011023	USPAT;	2004/07/26
			US-PGPUB;	15:09
			EPO; JPO;	
	1		DERWENT;	ļ
			IBM_TDB	
-	33	(714/704.ccls. and @ad<=20011023) and	USPAT;	2004/07/26
		tester	US-PGPUB;	15:35
			EPO; JPO;	
			DERWENT;	
			IBM TDB	

